	Ū	1	PT	P	D	ocument	ID	Issue	Date	Pages
1	☒				US A1	20020089	332	200207	11	9
2	×				us	5825035	Α	199810	20	58
3	⊠				US	5583344	A	199612	10	43
4	☒				US	5504340	A	199604	02	45
5	⊠				US	5426299	A	199506	20	9
6	⊠				US	5223711	Α	199306	29	8
7	⊠				US	5185523	A	199302	09	8
8	⊠				US	4714891	Α	198712	22	32
9	⊠				US A	20030049	937	200303	12	12
10	×				EP	960431 E	3	199808	20	1
11	⊠				JP	06101040	) A	199404	12	5

	Title	Current OR	Current XRef
1	Probe assembly for detecting an ion in a plasma generated in an ion source	324/466	
2	Processing method and apparatus using focused ion beam generating means	250/423R	250/492.21; 315/111.41; 315/111.81
3	Process method and apparatus using focused ion beam generating means	250/492.21	250/423R
4	Process method and apparatus using focused ion beam generating means	250/492.21	250/309; 250/423R
5	Inductive plasma mass spectrometer	250/281	250/283; 250/286; 250/299; 250/300; 250/397
6	Plasma sources mass spectrometry	250/281	250/282; 250/283; 250/397
7	Mass spectrometer for analyzing ultra trace element using plasma ion source	250/281	250/282; 250/288
8	Method and apparatus for improving the safety and extending the range of ionization gauge systems	324/459	307/326; 324/500; 361/42
9	Substrate surface treatment apparatus for executing surface treatment to a substrate in a reaction chamber, comprises detecting device, and controller for controlling reduction of energy of ions in plasma		
10	Element selective detection - with a micro plasma mass spectrometer having a plasma ion source in the high vacuum chamber		
11	Ion implantation appts in which peak current density of ion beam is decreased by adjusting gap distance between ion source plasma chamber and drawing out pole		

	Retrieval Classif	Inventor	s	С	2	3	4	5
1		Benveniste, Victor M.						
2		Mizumura, Michinobu et al.						
3		Mizumura, Michinobu et al.						
4		Mizumura, Michinobu et al.						
5		Nakagawa, Yoshitomo et al.						
6		Sanderson, Neil E. et al.						
7		Kitagawa, Masatoshi et al.						
8		Morrison, Jr., Charles F.						
9		NISHIDA, K et al.						
10		BREDE, C et al.						
11								

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1	us	20020089332
2	ŀ	5825035
3	us	5583344
4		5504340
5	US	5426299
6	us	5223711
7	US	5185523
8	US	4714891
9	us	20030049937
10	EP	960431 A0
11	JР	06101040 A

	ŭ	1	РТ	P	Document ID	Issue Date	Pages
12	$\boxtimes$				WO 9102376 A	19910221	8

	Title	Current OR	Current XRef
12	Plasma source mass spectrometer - has inductively or microwave coupled source and mass filter and low collector shielded from neutral particles		

	Retrieval Classif	Inventor	s	С	2	3	4	5
12		SANDERSON, N E et al.						

	Imag Doc. Displayed
12	US 5223711

	Туре	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	12	(plasma adj10 chamber)	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2003/10/14 10:55